TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74ACT00P,TC74ACT00F,TC74ACT00FN,TC74ACT00FT

Quad 2-Input NAND Gate

The TC74ACT00 is an advanced high speed CMOS 2-INPUT NAND GATE fabricated with silicon gate and double-layer metal wiring C^2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

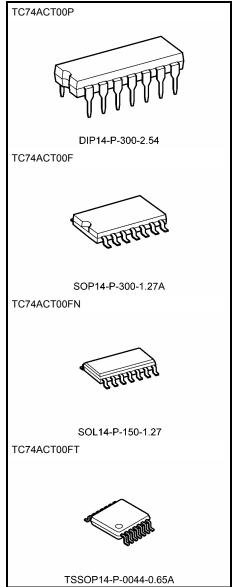
This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

- High speed: $t_{pd} = 4.0 \text{ ns}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 4 \mu A \text{ (max)}$ at $T_{a} = 25 \text{°C}$
- Compatible with TTL outputs: $V_{IL} = 0.8 \text{ V (max)}$ $V_{IH} = 2.0 \text{ V (min)}$
- Symmetrical output impedance: |IOH| = IOL = 24 mA (min) Capability of driving 50 Ω transmission lines.
- Balanced propagation delays: $t_pLH \simeq t_pHL$
- Pin and function compatible with 74F00

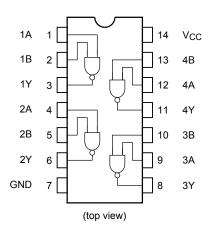
Note: xxxFN (JEDEC SOP) is not available in Japan.



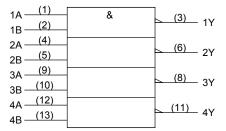
Weight

DIP14-P-300-2.54 : 0.96 g (typ.) SOP14-P-300-1.27A : 0.18 g (typ.) SOL14-P-150-1.27 : 0.12 g (typ.) TSSOP14-P-0044-0.65A : 0.06 g (typ.)

Pin Assignment



IEC Logic Symbol



Truth Table

Α	В	Υ
L	L	Н
L	Н	Н
Н	L	Н
Н	Н	L

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	−0.5 to 7.0	V
DC input voltage	V _{IN}	-0.5 to V _{CC} + 0.5	V
DC output voltage	Vout	-0.5 to V _{CC} + 0.5	V
Input diode current	I _{IK}	±20	mA
Output diode current	lok	±50	mA
DC output current	lout	±50	mA
DC V _{CC} /ground current	Icc	±100	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP/TSSOP)	mW
Storage temperature	T _{stg}	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = −40 to 65°C. From Ta = 65 to 85°C a derating factor of −10 mW/°C should be applied up to 300 mW.



Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	4.5 to 5.5	V
Input voltage	V _{IN}	0 to V _{CC}	V
Output voltage	V _{OUT}	0 to V _{CC}	V
Operating temperature	T _{opr}	-40 to 85	ů
Input rise and fall time	dt/dV	0 to 10	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics Symbol		Test Condition			Ta = 25°C			Ta = −40 to 85°C		Unit	
					V _C C (V)	Min	Тур.	Max	Min	Max	Unit
High-level input voltage	VIH	_			4.5 to 5.5	2.0	_	_	2.0	_	V
Low-level input voltage	V _{IL}		_		4.5 to 5.5	_	_	0.8	_	0.8	V
	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -50 μA		4.5	4.4	4.5	_	4.4	_	
High-level output voltage			I _{OH} = −24 mA		4.5	3.94	_	_	3.80	_	V
			I _{OH} = -75 mA (I	Note)	5.5	_	_	_	3.85	_	
		- VIN = VIH	I _{OL} = 50 μA		4.5	_	0.0	0.1	_	0.1	
Low-level output voltage	V _{OL}		I _{OL} = 24 mA		4.5	_	_	0.36	_	0.44	V
			I _{OL} = 75 mA (I	Note)	5.5	_	_	_	_	1.65	
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND			5.5	_	_	±0.1	_	±1.0	μΑ
Quiescent supply current	Icc	V _{IN} = V _{CC} or GND			5.5	_	_	4.0	_	40.0	μΑ
	IC	Per input: V _{IN} = 3.4 V Other input: V _{CC} or GND			5.5	-	_	1.35	_	1.5	mA

Note: This spec indicates the capability of driving 50 Ω transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

AC Characteristics ($C_L = 50 \text{ pF}$, $R_L = 500 \Omega$, input: $t_r = t_f = 3 \text{ ns}$)

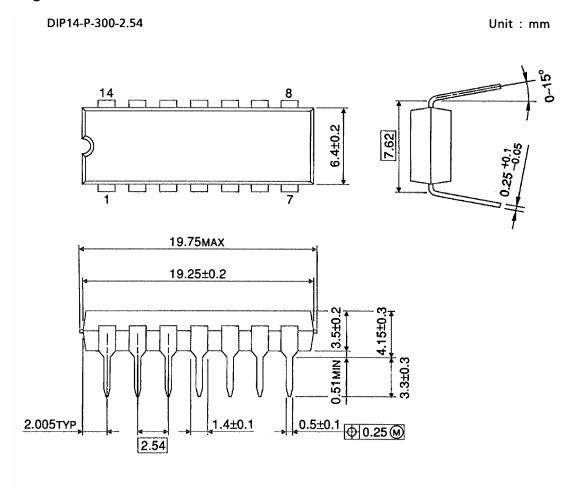
Characteristics Symbol	Symbol	Test Condition		Ta = 25°C			Ta = -40 to 85°C		Unit
		V _{CC} (V)	Min	Тур.	Max	Min	Max		
Propagation delay time	t _{pLH} t _{pHL}	_	5.0 ± 0.5	_	4.7	7.9	1.0	9.5	ns
Input capacitance	C _{IN}	_		_	5	10	_	10	pF
Power dissipation capacitance	C _{PD}		(Note)	_	23	_		_	pF

Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

ICC (opr) = CPD·VCC·fIN + ICC/4 (per gate)

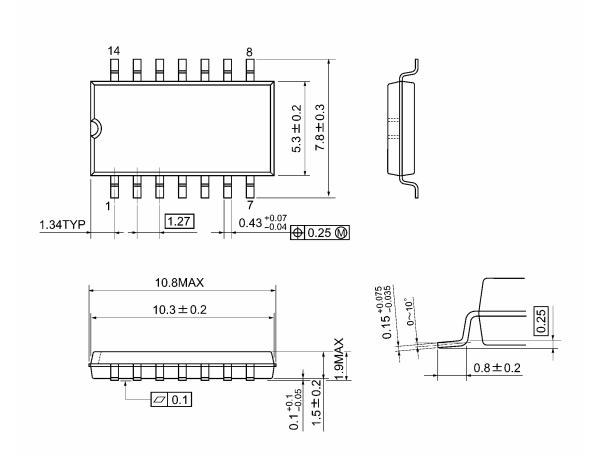
Package Dimensions



Weight: 0.96 g (typ.)

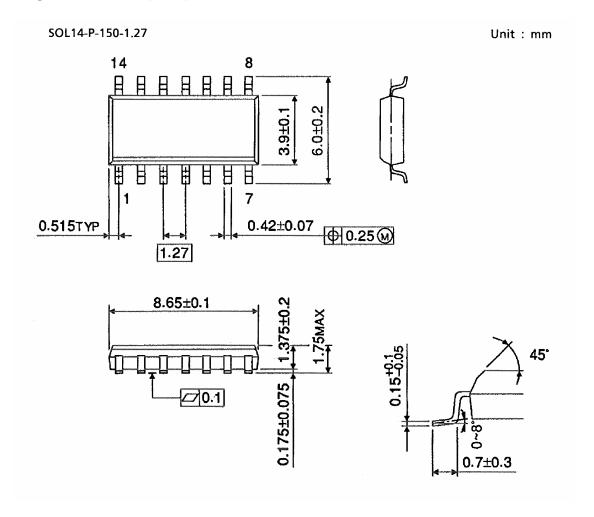
Package Dimensions

SOP14-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

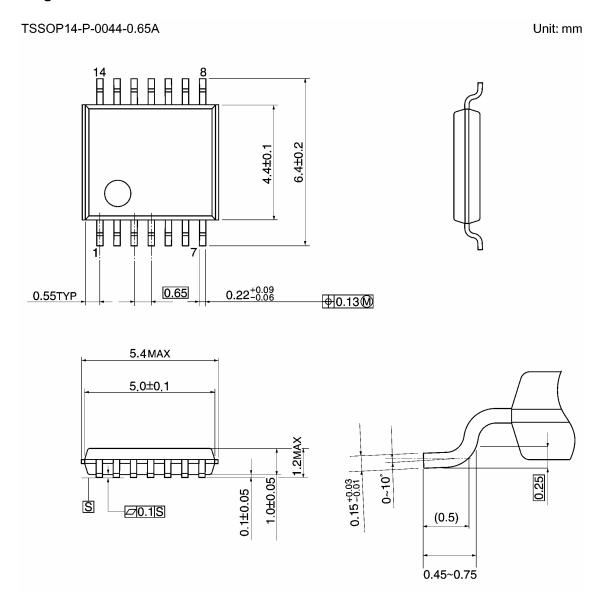
Package Dimensions (Note)



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

Package Dimensions



Weight: 0.06 g (typ.)

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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